

Patent Claims

1998/B004-1190

1. A method for carrying out a scattered light measurement, the optical beam guidance being set up such that the intensities of the scattered and transmitted components of the light are measured separately.
2. The method as claimed in claim 1, wherein the scattered and transmitted components of the incident light are separated by a specially shaped diaphragm.
3. The method as claimed in claims 1 and 2 constructed to the effect that the diaphragm has a region for accommodating a detector or for accommodating a beam guidance or deflection arrangement.
4. The method as claimed in claim 1, wherein the scattered and transmitted components of the incident light are separated by a specially constructed mirror inserted into the beam path with the accommodation of a beam guidance or deflection unit.
5. The method as claimed in claim 1, wherein the scattered and transmitted components of the incident light are separated by a specially machined lens inserted into the beam path with simultaneous accommodation of a diaphragm and beam guidance or deflection unit.
6. The method as claimed in claim 1, wherein the detector for measuring the intensity of the transmitted component is equipped with additional wavelength-selective components.

7. The method as claimed in claims 1 to 6, wherein the signals of the scattered and transmitted components are measured both temporally separately and simultaneously.

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8. The method as claimed in claims 1 to 5, wherein the intensity of the light source is readjusted by the light directly transmitted from the light source.

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9. The method as claimed in claims 1 to 5, wherein setting, testing and, if appropriate, correction of the position of a vessel for accommodating material to be measured, which vessel is moved through the measuring beam, are effected in such a way that, by means of step-by-step scanning of a vessel during its movement through the measuring beam, the transmitted signal is recorded as a function of the position of said vessel and is used to define the position of the accommodating vessel relative to the measuring beam.

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10. The method as claimed in claims 1 to 9, wherein the method can be used as in-process control for the purpose of validation in automatic diagnostic analyzers.

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11. The method as claimed in claims 1 to 9 for use in analysis.

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12. The method as claimed in claims 1 to 9 for use in in-vitro diagnosis.